

Semiconductor thin film

Art. ID	NIST-2841
Unit	disc
Deliverydetails	No Dangerous Good /not restricted

Description

This Standard Reference Material (SRM®) is intended for use as a reference standard for analytical methods that measure the composition of thin films, such as electron microprobe analysis (EMPA), photoluminescence (PL), auger electron spectroscopy (AES) and X-ray photoelectron spectroscopy (XPS). A unit of NIST-2841 consists of an epitaxial layer of Al_xGa_{1-x}As with certified Al mole fraction x grown on a gallium arsenide (GaAs) substrate mounted to a stainless steel disk by the use of adhesive tape. Each unit is sealed in a Mylar envelope containing a nitrogen atmosphere. /// Sample value(s) - please ask for current certificate.

Text/Information	Analyte/Parameter	CAS number	Concentration/Value	Unit	Method	Source
Individually measured	Certified Value (mole fraction) for Aluminum					